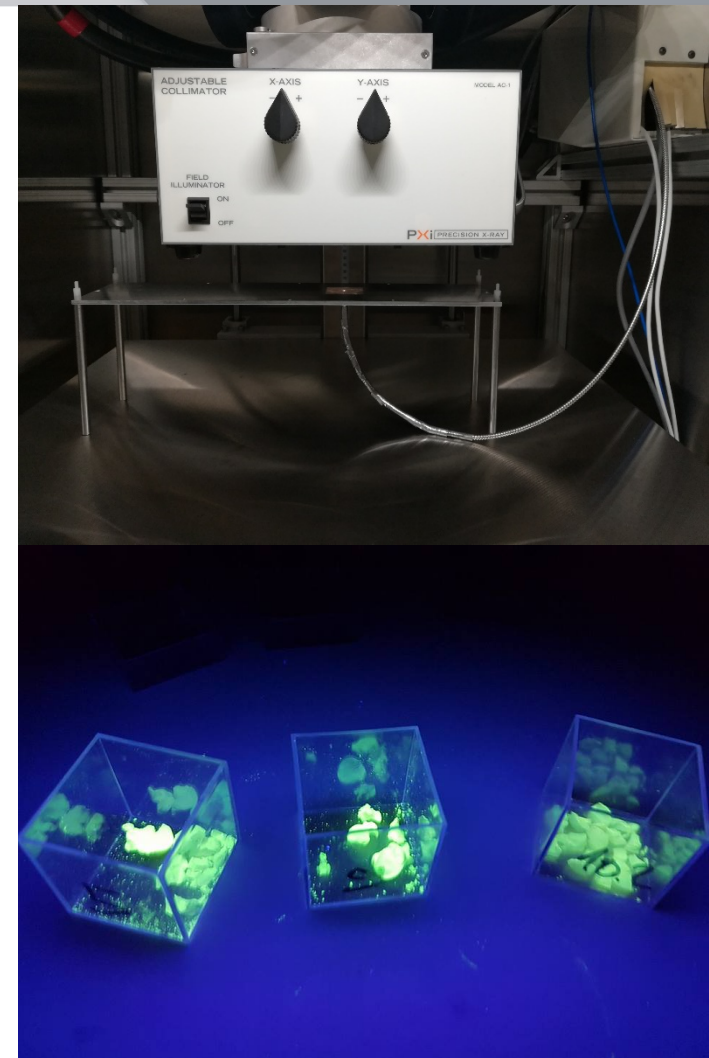


DEVELOPMENT AND SYNTHESIS OF A NEW KIND OF LUMINESCENT MATERIAL FOR DOSIMETRY

Bouisri Samir

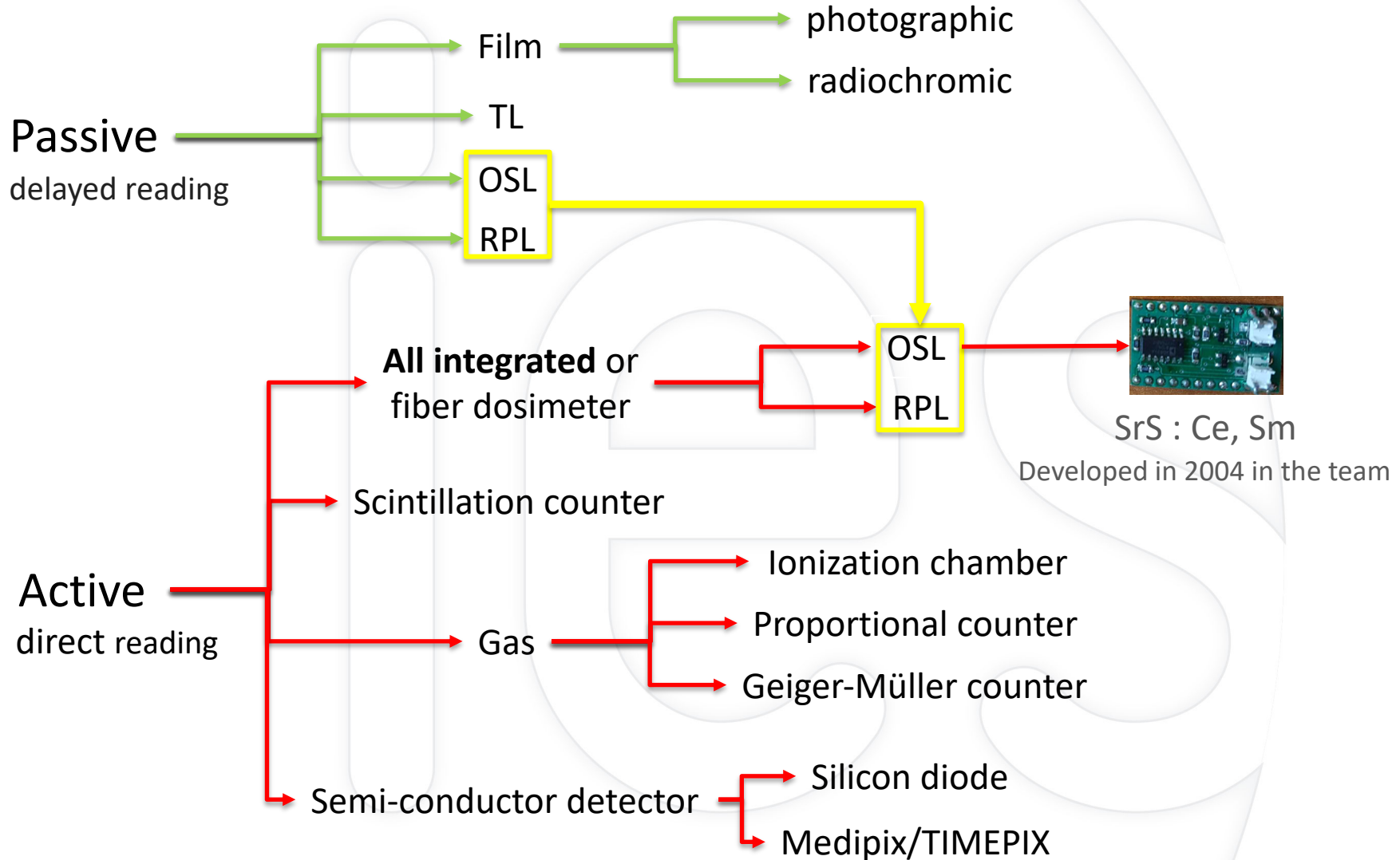
PHD thesis
(start : october 2017)

Supervisor :
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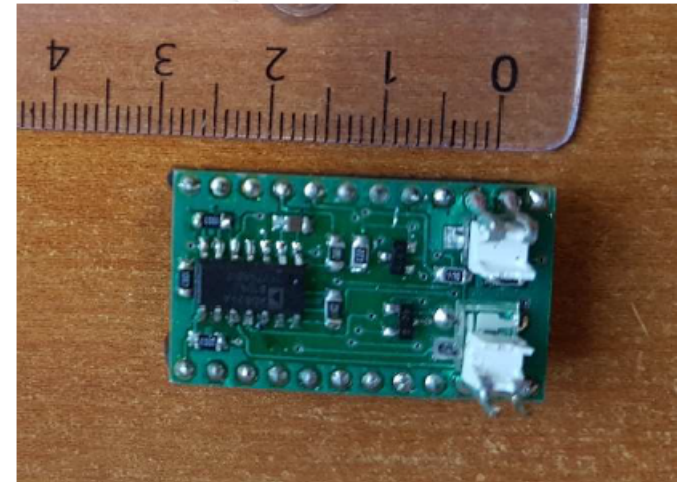
Develop luminescent materials for dosimetry in order to realize thin layer and integrate them in a microelectronic process (SoC)

Using a reproducible and reliable manufacturing process



Pros

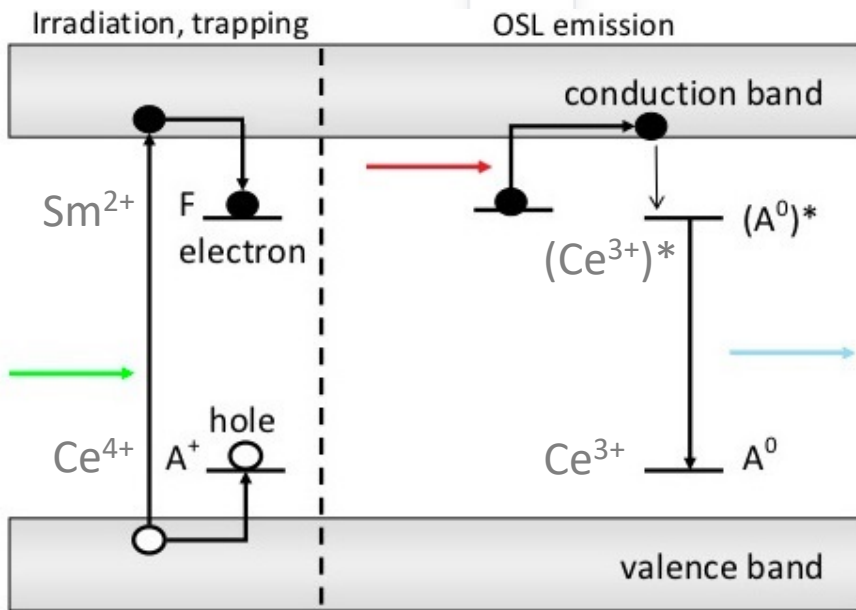
- Good Sensivity and dynamics
 - 10 μ Gy to 300 Gy (saturation), linear to 100 Gy
- Compact



Cons

- Reproducibility of the process and integrability
 - Powder (deposited by screen painting)
 - Sulfur (oxidation -> not inert)

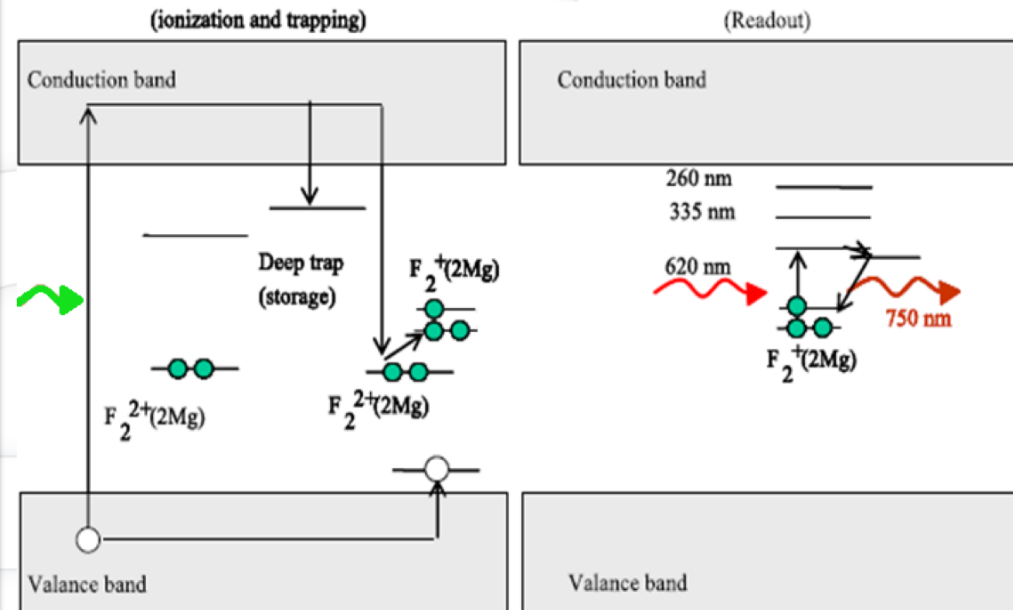
Optically Stimulated Luminescence



- OSL (visible) F Electron trap center
- Stimulation (IR) A^+ Hole trap center
- Ionizing radiation A^0 Luminescent center

SrS : Ce,Sm

Radio-PhotoLuminescence



- RPL (visible)
 - Stimulation (UV)
 - Ionizing radiation
- $\text{Al}_2\text{O}_3:\text{C,Mg}$

OSL

Pros

- Can be reset by light beam
- Multiple readings...

Cons

- Fading (loss of information due to ambient temperature)
- ...but with loss of information

RPL

Pros

- No fading (deep trap)
- Multiple readings without loss of information

Cons

- Need to be annealed at high temperature to be reset

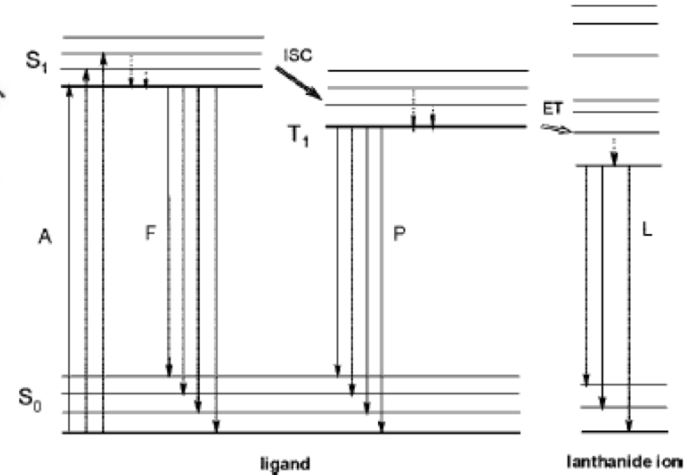
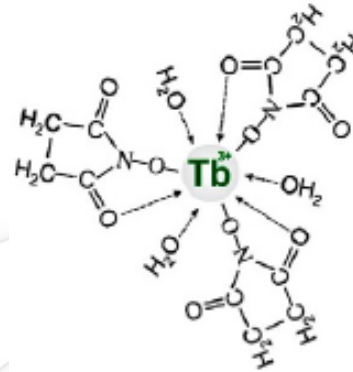
- Easy to integrate
- Can be reset without damaging the system
- Good sensitivity and dynamics
 - Depend on the aimed application
 - It will be easier to adjust this parameters, mastering the fabrication process
- Low fading

- Compatible with microelectronic process



• Terbium

- $\lambda_{\text{emission}}$ does not depend on the crystalline environment
- But a low molar absorptivity
→ Antenna effect : ligand (NHSl)



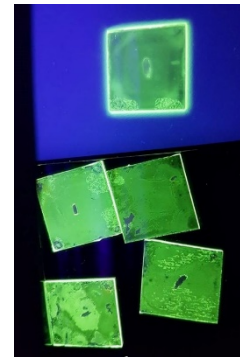
• Aerogel and Xerogel

- Sol-gel process + supercritical drying (aerogel) or air drying (xerogel)
- Large emission area due to his high porosity
- Easily shapable

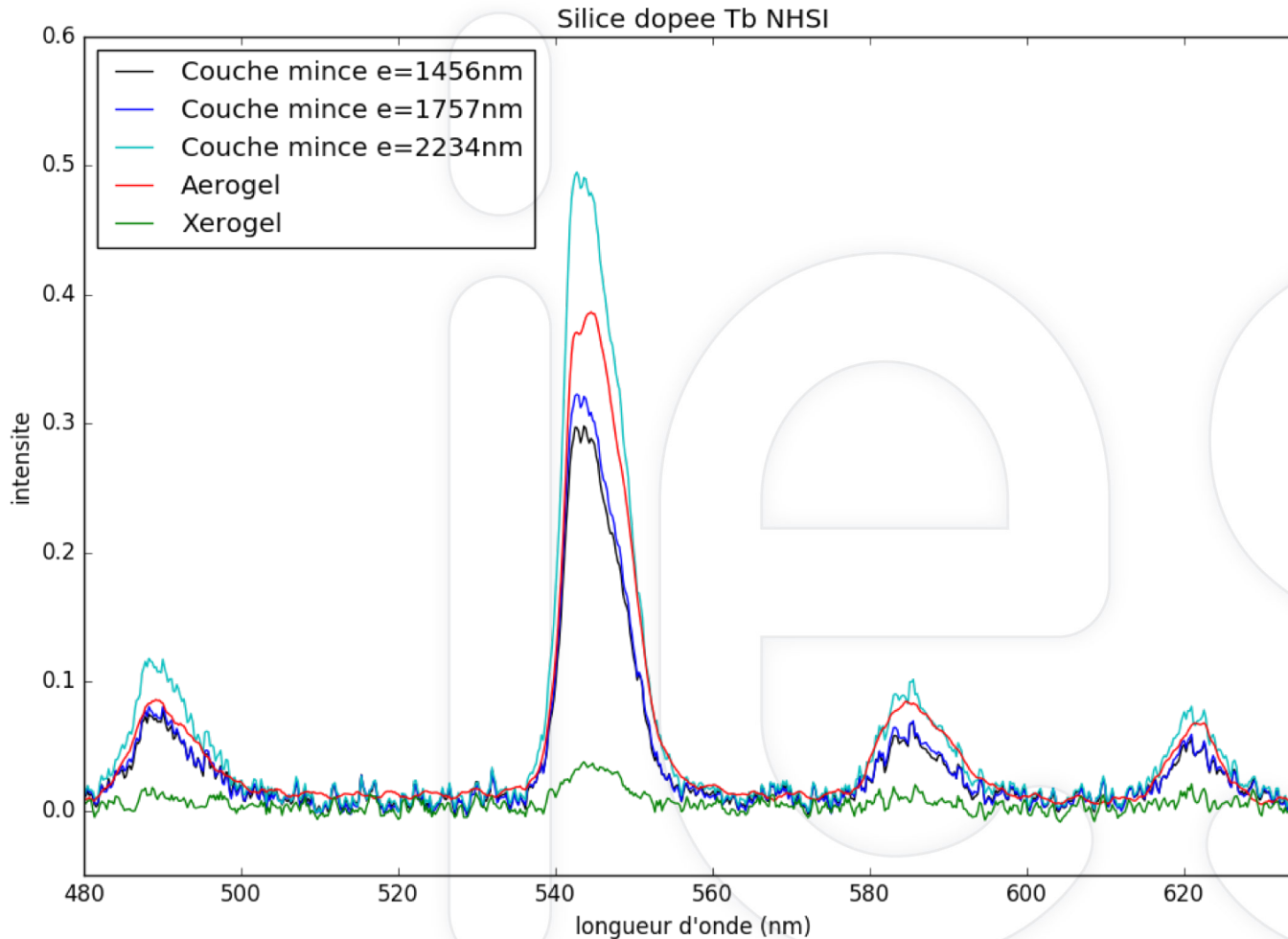


• Thin layers

- deposited by spin coating
- 1500 - 2200 nm thick



Under UV (254 nm)



PL spectra under
UV (254 nm)

- No RL observed under Xrays
 - Sensivity of the detection system ?
 - Other mechanism ?
 - Fluorescence X
 - Quenching

$^5D_4 \rightarrow ^7F_6$
488 nm

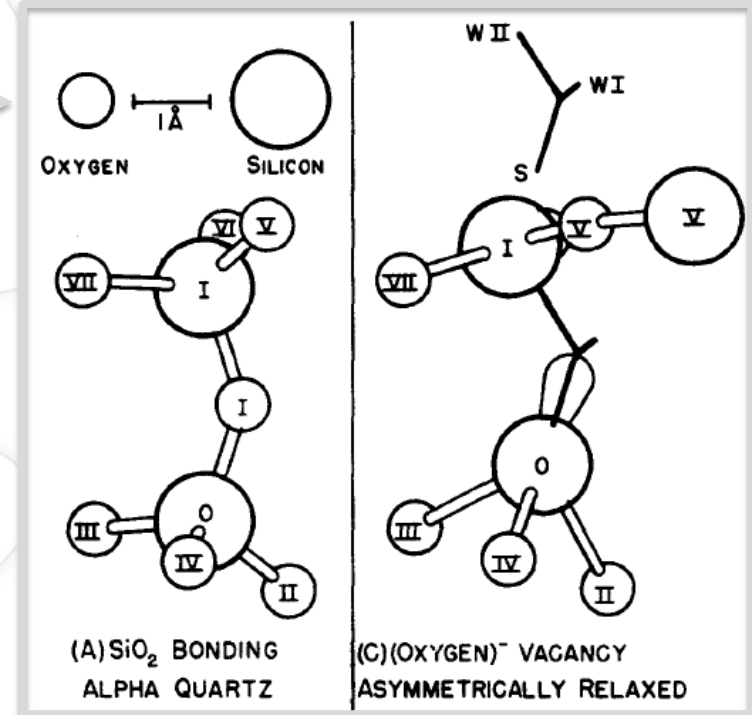
$^5D_4 \rightarrow ^7F_5$
543 nm

$^5D_4 \rightarrow ^7F_4$
584 nm

$^5D_4 \rightarrow ^7F_2$
618 nm

Tb³⁺ radiative
emissions

- SiO_2 + traces of H, Li, Na, K, Al, Ga, Ti, Fe, Ge, P growing on a Si substrate with sol-gel process
- Radiation-induced defects in quartz
 - E_1' center : O^- vacancy (electron trap)
 - Al center : Al^{3+} in substitution of Si^{4+} (hole trap)
 - ...



- We want to develop luminescent materials for dosimetry
- 2 types of materials are studied (amorphous silica and quartz)
- First results on amorphous silica didn't show any luminescence under Xrays
 - A more sensitive detection system based on a PM and an experiment to see if Xray fluorescence occurs in the material are in development
- Quartz samples are in development, first samples will be received in may